

EMC TEST REPORT

According to FCC CFR47 Part 18 Subpart C

JOB Number :

1. This test reports does not constitute an endorsement by NIST/NVLAP or U.S Government.
2. This test report is to certify that the tested device properly complies with the requirements of FCC Rules and Regulations Part 18 CFR47 Subpart C Intentional Radiators.
All tests necessary to show compliance to the requirements were and these results met the specifications requirement.

This laboratory is registered by the NIST/NVLAP, U.S.A.
The test reported herein have been performed in accordance with its terms of registration.



1. Applicant Name : SAMSUNG ELECTRONICS CO., LTD.
416 Maetan 3 Dong, YoungTong-Ku, Suwon City, Kyungki Do, Korea, 443-742

2. Identification of tested device
2.1 FCC ID : ACLAP6H61
2.2 Device Name : MICROWAVE OVEN
2.3 Trade Name : Shanghai Matsushita Microwave Oven Co., Ltd
2.4 Model Number : NN-H764WF
2.5 RF Output Power : 1250 W (by IEC 705 method)

3. Test Procedure and Items
3.1 FCC/OST MP-5 : 1986

4. Issued Date : December 30, 2003

Tested by: J. Y Park
Jay Yong, PARK / Test Engineer

Reviewed by: N. C. Park
No Cheon, PARK / Manager of EMC Lab.

Authorised by: K. B. Chung
Kyu Baek, CHUNG / Chief of EMC Lab.

This reports shall not be reproduced except in full, without the written approval of SEC EMC Testing laboratory.

TABLE OF CONTENTS

- 1. Product Description**
- 2. Test Facility**
- 3. Accreditation and Listing**
- 4. Radio Noise Emission Measurement Procedures/Results**
 - 4.1 Radiation Hazard Measurement**
 - 4.2 Input Power Measurement**
 - 4.3 RF Output Power Measurement**
 - 4.4 Operation Frequency Measurement**
 - 4.4.1 Variation in Operating Frequency with Time Measurement**
 - 4.4.2 Variation in Operating Frequency with Voltage Measurement**
 - 4.4.3 Variation in Operating Frequency with Time Plot**
 - 4.4.4 Variation in Operating Frequency with Voltage Plot(96Vac)**
 - 4.4.5 Variation in Operating Frequency with Voltage Plot(120Vac)**
 - 4.4.6 Variation in Operating Frequency with Voltage Plot(150Vac)**
 - 4.5 Radiated Emission Measurement**
 - 4.5.1 Radiated Emission Measurement Procedure**
 - 4.5.2 Radiated Emission Measurement Configuration**
 - 4.5.3 Radiated Emission Measurement Data(30 - 1000MHz)**
 - 4.5.4 Radiated Emission Measurement Data(1 - 25GHz)**
- 5. Measurement Equipment List**

1. Product Description

The equipment under test is a microwave oven sold for consumer use. Model NN-H764W is a 1250 W microwave oven with digital controls. Installation Type: Inverter

< Magnetron >

Model : OM75PI(21) manufactured by Samsung Electronic Co., Ltd.

2. Test Facility

The Semi-anechoic chamber and Conducted measurement facilities used to collect the radiated data are located at 416 Maetan 3 Dong, Paldal-Ku, Suwon City, Kyungki Do, Korea.

The sites are constructed in conformance with the requirements of ANSI C63.4 and CISPR Publication 22.

3. Accreditation and Listing

The test facilities used to perform radiated and conducted emissions tests are accredited by National Voluntary Laboratory Accreditation Program for the specific of accreditation under Lab Code: 200447-0 to perform Electromagnetic Interference tests according to FCC PART 15 and CISPR 22 requirements.

No part of this report may be used to claim or imply product endorsement by NVLAP or any agency of the US Government. In addition, the test facilities are listed with Federal Communications Commission(Registration Number:98856, Anechoic Chamber #1).